

<b>Notice of References Cited</b>	Application/Control No. 10/003,109	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Kim-Kwok CHU	Art Unit 2653	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,167,012	12-2000	Van Den Enden et al.	369/47.1
	B	US-6,097,684	08-2000	Oohata et al.	369/53.22
	C	US-6,252,845	06-2001	Hino et al.	369/275.3
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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